

Notice of References Cited	Application/Control No. 10/628,228	Applicant(s)/Patent Under Reexamination TAKENAKA, HIDEKI	
	Examiner Alex Liew	Art Unit 2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,164,992	11-1992	Turk et al.	382/118
*	B	US-2004/0145657	07-2004	Yamamoto et al.	348/143
*	C	US-5,771,307	06-1998	Lu et al.	382/116
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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	P					
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NON-PATENT DOCUMENTS

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